

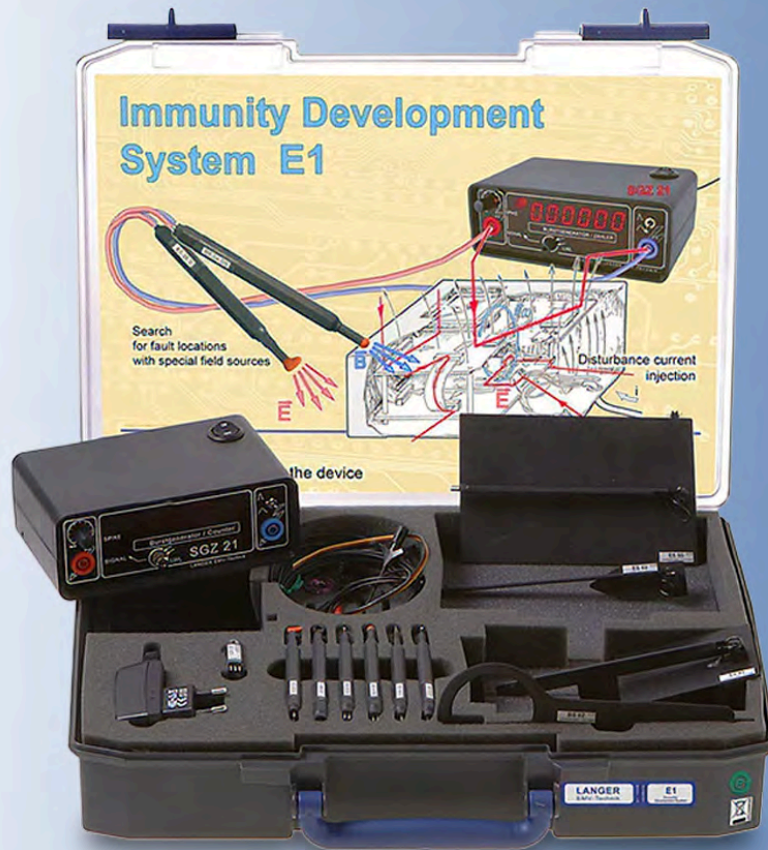


news & updates July 2026 | Issue 29

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LANGER
EMV-Technik



CEO's Corner

Dear Colleague,



Are you involved in EMI testing? Have you experienced the pain of failing EMI and EMC limits during product testing at an outside lab?

Electric or magnetic field sources are crucial for evaluating the electromagnetic compatibility of electronic assemblies. Traditionally, this process begins with low-resolution sources that influence broad areas and identify general fault zones. However, pinpointing exact issues within these zones has required higher resolution sources that deliver precise, concentrated field beams. That is why the [E1 Immunity system](#) has been designed to streamline this process by integrating a comprehensive set of focused, localized tools for EMI investigations.

Alan Lowne

CEO, Saelig Company Inc.

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ICR HH500-6 Near-Field Microprobe Kit 2MHz-6GHz

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Saelig Website



* Founded Saelig in 1988 to search the world for unique electronic control and instrumentation equipment including: oscilloscopes, PC and RF spectrum analyzers, USB and logic analyzers, EMC test RF sources, EMC test systems, GPIB and IEC controllers, PCB test, high-voltage industrial panel PCB EM enclosures, USB serial converter cables, etc.*

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The [Langer EMV-Technik E1 Immunity development system](#) has been specifically designed for EMI investigations in printed circuit boards and electronic modules, detecting burst and ESD sensitivities, and checking the effect of EMC measures. The E1 is a set of EMC tools that can simulate interference processes when testing an electronic product. Disturbance currents, electric and magnetic fields can be injected directly into the electronic modules in different ways to determine the susceptible structures on the circuit board, understand the coupling mechanism and enable the implementation of optimum modifications if needed. The E1 Set includes a Burst Generator; three magnetic field sources for localizing weak spots in a layout; five E-Field sources for testing

sensitive weak areas, a magnetic field probe; and an Optical Sensor Digital Probe for nonreactive transmissions of binary signals out of the DUT.



Developers can use the E1 set to quickly identify the results of burst and ESD interference. This allows the developer to design suitable measures to solve the causes of the interference. It can also be used to test the effectiveness of the measures taken. The E1 test set-up is small and fits easily on a developer's desk. The E1 set user manual describes EMC mechanisms and provides detailed descriptions of basic measuring strategies for interference suppression in printed circuit boards. The E1 set includes a generator to generate burst and ESD disturbances.

The main problem with failed EMC tests is that the electronics behave like a 'black box'. A disturbance may enter the electronics at a specific point, but the internal effects that lead to the failure are not visible. Testing at the earliest opportunity helps troubleshooting and analysis before compliance tests fail. The E1 set can create local burst and ESD disturbances, enabling developers to effectively address and mitigate specific interference issues during the development phase. The differential output of the burst generator allows engineers to inject disturbance currents into specific areas of the electronics. This is helpful for initially identifying areas of the circuitry that are not subject to failures and can reduce the complexity of the test setup. Then the field sources of the E1 set can be used to target and localize weak spots, right down to the pin level of IC's.

Also supplied with the E1 set is a user manual that thoroughly covers [EMC](#) mechanisms and provides detailed instructions on basic measuring strategies for interference suppression in PCBs.

The E1 solution is very affordable when compared to the cost of conventional testing equipment and the rates charged by test labs

To view a video of the features of the Langer EMV-E1 Set, click the image >



More product details here:

[Langer EMV-Technik E1 Set Immunity Development System \(\\$6,689.79\) : Saelig Online Store](#)

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